•	Search Notes	
		II
		I
		ı
		II

Application/Control No.	Applicant(s)/Patent und Reexamination	ier
10/788,756	LIU ET AL.	
Examiner	Art Unit	
Ramsey Zacharia	1773	

SEARCHED			
Class	Subclass	Date	Examiner
		-	

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
EAST int		8/30/2006	REZ

SEARCH I (INCLUDING SEAR)
	DATE	EXMR
eDAN inventor search	8/30/2006	REZ
·		